Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/790,871	TATEIWA, AKIHIKO	
Examiner	Art Unit	
James D. Stein	2874	

James D. Stein

OFAROUER						
	SEARCHED .					
Class	Subclass	Date	Examiner			
385	27,31,39, 42,49,50, 51,78,95	6/15/2005	JDS			
385	124	6/15/2005	JDS			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		,		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
See attached EAST search history	6/15/2005	JDS		
IEEE, INSPEC: collimator, GRIN fiber, graded index fiber, mirror	6/15/2005	JDS		